

## INTERNATIONAL SEARCH REPORT

International application No.

PCT/US04/25332

A. CLASSIFICATION OF SUBJECT MATTER  IPC(7) : C08G 75/00; C12Q 1/00; C23F 1/00; G01N 23/00; G01R 31/26; G21K 7/00; H01B 1/02, 1/08; H01L 21/66  US CL : 216/2; 250/307; 252/518.1; 435/4; 438/14; 528/380				
	International Patent Classification (IPC) or to both nati			
B. FIELDS SEARCHED				
Minimum documentation searched (classification system followed by classification symbols) U.S.: 216/2; 250/307; 252/518.1; 435/4; 438/14; 528/380				
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched				
Electronic data base consulted during the international search (name of data base and, where practicable, search terms used) Please See Continuation Sheet				
C. DOCU				
Category *	Citation of document, with indication, where ap		Relevant to claim No.	
x	US 2001/0044156 A1 (Kelly et al) 22 November 200		1, 13-15, 17, 18, 20-23,	
 Y	[0011], [0012]; page 3, paragraph [0014]; page 4, par [0050].	agraph [0030]; page 7, paragraph	25-28	
•	[0030].		2-7	
Y	BAN, L.L. et al. Determining the Polymer Domain Structure of TPE Blends by Microscopy		2-7	
	Techniques. Rubber World. January 1993, Vol 207. No. 4, pages 20-22.			
A			29	
Y	VAN DER LINDEN, H. et al. Development of Stimulus-sensitive Hydrogels Suitable for Actuators and Sensors in Microanalytical Devices. Sensors and Materials. 2002, Vol 14. No. 3, pages 129-139, especially page 135.		8	
A	KELLY, T.F. et al. Local Electrode Atom Probes. Ma No. 1/2, pages 59-85, especially page 67.	sterials Characterization. 2000, Vol 44.	9-12, 19, 24	
A	MARUYAMA, T. et al. FIM and Atom-probe Study of Polymers. Journal de Physique. November 1987, C6, pages C6-269/C6-274, especially page C6-270.		12, 16, 19	
Further	documents are listed in the continuation of Box C.	See patent family annex.		
Special categories of cited documents:		"T" later document published after the inte date and not in conflict with the applic		
"A" document defining the general state of the art which is not considered to be of particular relevance		principle or theory underlying the inve		
"E" earlier application or patent published on or after the international filing date		"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone		
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"O" document referring to an oral disclosure, use, exhibition or other means		being obvious to a person skilled in the		
"P" document published prior to the international filing date but later than the priority date claimed		"&" document member of the same patent family		
Date of the ac	ctual completion of the international search	Date of mailing of the international search	h report	
13 June 2005	(13.06.2005)	ZZ JUL	. 20 <b>05</b>	
Name and mailing address of the ISA/US		Authorized officer		
Mail Stop PCT, Attn: ISA/US Commissioner for Patents		Susan E. Pepper Susan E. Peppe		
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Facsimile No. (571) 273-0419				

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Continuation of B. FIELDS SEARCHED Item 3:  EAST: US-PG/SUBJUAT, EPO, JPO, DEERWENT; STN: REGISTRY, CAPLUS, BIOSIS; Search terms of subjuard, end of subjuard in the subjuard of subjuard in the subjuard in t		International application No.
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